DAkkS
Deutsche
Akkreditierungsstelle

Deutsche Akkreditierungsstelle GmbH

Annex to the Accreditation Certificate D-PL-17283-01-00 according to DIN EN ISO/IEC 17025:2018

Valid from: 07.09.2020

Date of issue: 07.09.2020

Holder of certificate:

TASCON Gesellschaft für Oberflächen- und Materialcharakterisierung mbH

with the locations

Mendelstraße 17, 48149 Münster
Otto-Volger-Straße 19, 65843 Sulzbach/Ts.

Tests in the fields:

physical-chemical analysis of the chemical, elemental and molecular composition of surfaces, interfaces, near-surface layers, complex layer systems, trace impurities and near-surface volume material, including the lateral and depth distribution on solids, cross sections, powders, particles, fibres, liquids and paints by means of Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS) and X-Ray Photoelectron Spectroscopy (XPS / ESCA); determination of the roughness of surfaces by means of Optical Profilometry

Within the given testing field marked with ** the testing laboratory is permitted, without being required to inform and obtain prior approval from DAkkS, the modification and refinement of testing methods. The listed testing methods are exemplary.
The testing laboratory maintains a current list of all testing procedures within the flexible scope of accreditation.

Within the scope of accreditation marked with *, the testing laboratory is permitted, without being to inform and obtain prior approval from DAkkS, to use standards or equivalent testing methods listed here with different issue dates. The testing laboratory maintains a current list of all testing procedures within the flexible scope of accreditation.**

This document is a translation. The definitive version is the original German annex to the accreditation certificate.

Abbreviations used: see last page

The certificate together with its annex reflects the status at the time of the date of issue. The current status of the scope of accreditation can be found in the database of accredited bodies of Deutsche Akkreditierungsstelle GmbH.
https://www.dakks.de/en/content/accredited-bodies-dakks

The test procedures are marked with the following symbols for the locations at which these are in use:

MS = Münster MTK = Sulzbach/Ts.

1 Determination of the chemical, elemental and molecular composition of surfaces, interfaces, near-surface layers, complex layer systems, trace impurities and near-surface volume material, including the lateral and depth distribution on solids, cross sections, powders, particles, fibres, liquids and paints by means of Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS) **

VA-OG-AM-ToF-SIMS-Spektrenakquisition / 3 2017-02	Chemical characterisation of surfaces by means of Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS): Spectrometry	MS
VA-OG-AM-ToF-SIMS-Imageakquisition / 3 2017-02	Chemical characterisation of surfaces by means of Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS): Imaging	MS
VA-OG-AM-ToF-SIMS-Tiefenprofilakquisition / 2 2017-02	Chemical characterisation of surfaces by means of Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS): Depth Profiling	MS
VA-OG-AB-ToF-SIMS-Quantifizierung-von-B-in-Si / 2 2017-02	Quantitative Detection of Boron in Silicon (ToF-SIMS)	MS

2 Determination of the chemical, elemental and molecular composition of surfaces, interfaces, near-surface layers, complex layer systems, trace impurities and near-surface volume material, including the lateral and depth distribution on solids, cross sections, powders, particles, fibres, liquids and paints by means of X-Ray Photoelectron Spectroscopy (XPS / ESCA) **

VA-OG-AB-XPS-Messen- und-Auswerten-Spektroskopie / 2 2017-02	XPS/ESCA measurement and data evaluation: Spectroscopy	MTK
VA-OG-AB-XPS-Messen-und-Auswerten-Imaging / 0 2017-02	XPS/ESCA measurement and data evaluation: Imaging	MTK

-Translation-

Valid from: 07.09.2020
Date of issue: 07.09.2020